



Short Course on Microwave Measurements

Dec. 9 – 10, 2008
Portland, Oregon



AGENDA

Tuesday, December 9

- 7:30 a.m. – 8:00 a.m. **Registration**
- 8:00 a.m. – 8:10 a.m. **Welcome and Introduction**
Dominique Schreurs – K.U.Leuven
- 8:10 a.m. – 9:10a.m. **Connectorized S-Parameter Measurements**
Jon Martens – Anritsu
- 9:10 a.m. – 10:10a.m. **On-wafer S-Parameter Measurements**
Dylan Williams – NIST
- 10:10 a.m. – 10:30 a.m. **Break**
- 10:30 a.m. – 11:30 a.m. **Microwave Power Measurements**
Tom Crowley – NIST
- 11:30 a.m. – 12:30 p.m. **Thermal Noise Measurements**
David Walker – NIST
- 12:30 p.m. – 1:30 p.m. **Lunch**
- 1:30 p.m. – 2:30 p.m. **Large-Signal Measurements**
Dominique Schreurs – K.U.Leuven
- 2:30 p.m. – 3:30 p.m. **Phase Noise Measurements**
Craig Nelson – NIST
- 3:30 p.m. – 4:00 p.m. **Break**
- 4:00 p.m. – 5:00 p.m. **Measurement Uncertainty**
Nick Ridler – NPL



Short Course on Microwave Measurements

Dec. 9 – 10, 2008
Portland, Oregon



AGENDA

Wednesday, December 10

- 8:00 a.m. – 9:00 a.m. **Oscilloscope Measurements**
Paul Hale – NIST
- 9:00 a.m. – 10:00 a.m. **Time Domain Network Analyzer Measurements**
Joel Dunsmore – Agilent Technologies
- 10:00 a.m. – 10:20 a.m. **Break**
- 10:20 a.m. – 11:20 p.m. **Signal Integrity Measurements**
Brett Grossman – Intel
- 11:20 a.m. – 12:20 p.m. **Power Integrity Measurements**
Michael Hill – Intel